## Applicant(s)/Patent Under Application/Control No. Reexamination 10/650,458 ROEHR ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2187 Hiep T. Nguyen **U.S. PATENT DOCUMENTS** Date **Document Number** Name Classification Country Code-Number-Kind Code MM-YYYY 06-2004 Rudelic, John C. 711/118 US-2004/0123033 Α 365/200 04-2004 Harari et al. В US-2004/0080988 С US-US-D US-Ε US-F US-G US-Н US-J US-US-Κ US-US-FOREIGN PATENT DOCUMENTS Date **Document Number** Classification Name Country Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Х